

QUERY CONTROL FORM		RTIS USE ONLY	
Application No. <u>09980432</u>	Prepared by <u>ewc</u>	Tracking Number <u>05964381</u>	
Examiner-GAU <u>Nguyen</u>	Date <u>8-10-04</u>	Week Date <u>6-14-04</u>	
<u>2881</u>	No. of queries <u>-2-</u>	IFW	

## JACKET

a. Serial No.	f. Foreign Priority	k. Print Claim(s)	<u>p. PTO-1449</u>
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	<u>t. Other</u>

## SPECIFICATION

- a. Page Missing
- b. Text Continuity
- c. Holes through Data
- d. Other Missing Text
- e. Illegible Text
- f. Duplicate Text
- g. Brief Description
- h. Sequence Listing
- i. Appendix
- j. Amendments
- k. Other

## MESSAGE

ATTENTION: CHIEF DRAFTSPERSON

1) Drawing numbers are not shown on drawings of 11-28-01 for Fig 2 and Fig 23C.

2) PTO-1449 - Please either initial or line through citations. see attached copy.

Thank you  
ewc

## CLAIMS

- a. Claim(s) Missing
- b. Improper Dependency
- c. Duplicate Numbers
- d. Incorrect Numbering
- e. Index Disagrees
- f. Punctuation
- g. Amendments
- h. Bracketing
- i. Missing Text
- j. Duplicate Text
- k. Other

initials

## RESPONSE

initials

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. GIVAR7.001APC	APPLICATION NO. 09/880,432
INFORMATION DISCLOSURE STATEMENT BY APPLICANT  (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Givargizov, et al.	
		FILING DATE November 29, 2001	GROUP Unknown

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
	5,742,377	04/21/88	Minne, et al.			
	5,825,122	10/20/88	Givargizov, et al.			
	6,308,734	10/23/01	Givargizov			

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	WO 88/42101	12/27/88	PCT				
	WO 89/58925	11/18/89	PCT				

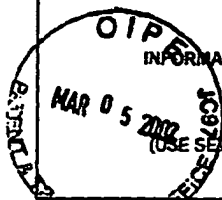
## OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

EXAMINER INITIAL	
	C.A. Spindt, et al., <i>Physical properties of thin-film field emission cathodes with molybdenum cones</i> , J. Appl. Phys., 47, pp. 5248-5283 (1976)
	P. Grütter, et al., <i>Batch fabricated sensors for magnetic force microscopy</i> , Appl. Phys. Lett. 57, pp. 1820-1822 (1990)
	D.W. Abraham, et al., <i>Lateral dopant profiling in semiconductors by force microscopy using capacitive detection</i> , J. Vac. Sci. Technol., 89, pp. 703-706 (1991)
	K.L. Lee, et al., <i>Submicron Si trench profiling with an electron-beam fabricated atomic force microscope tip</i> , J. Vac. Sci. Technol., 89, pp. 3352-3568 (1991)
	E.I. Givargizov, <i>Ultrasharp tips for field emission applications prepared by the vapor-liquid-solid growth technique</i> , J. Vac. Sci. Technol., 811, pp. 449-453 (1993)

EXAMINER

DATE CONSIDERED

\*EXAMINER: INITIAL IF CITATION CONSIDERED. WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE 	ATTY. DOCKET NO. GIVAR7.001APC	APPLICATION NO. 08/980,432
	APPLICANT Givargizov, et al.	
	FILING DATE November 29, 2001	GROUP Unknown

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
	C.D. Frisbie, et al., <i>Functional group imaging by chemical force microscopy</i> , Science, 265, pp. 2071-2074 (1994)
	V.A. Bykov, et al., <i>New devices and possibilities in a scanning probe microscopy</i> , in: Proc. Russian 1999 Conf. On SPM, Nizhnii Novgorod, pp. 132-133 (March 1999)
	J. Browning, <i>Field emission display development and testing</i> , Proc. Of the 8th Intern. Conf. On Vacuum Microelectronics (Portland, USA), pp. 1-8 (1995)
	Y. Huang, et al., <i>Quantitative two-dimensional dopant profiling of abrupt dopant profiles by cross-sectional scanning capacitance microscopy</i> , J. Vac. Sci. Technol. A14, pp. 1168-1171 (1998)
	J.H. Hafner, et al., <i>Growth of nanotubes for probe microscopy tips</i> , Nature 398, pp. 761-762 (1999)
	P. Leitnerbach, et al., <i>Fabrication and characterization of advanced probes for magnetic force microscopy</i> , Appl. Surf. Sci., 144-145, pp. 492-496 (1999)
	L. Abelman, et al., <i>Analysis of the limit of resolution in magnetic force microscopy using EBID tips</i> , a paper presented to Intern. STM Conf., Seoul, Korea, Ext. Abstr., pp. 477-478 (1999)
	V.V. Dremov, et al., <i>An alternative working mode of SPM at surface investigations</i> , in: Proc. Russian 1999 Conf. On SPM, Nizhnii Novgorod, pp. 404-410 (March 1999)
	E.I. Givargizov, et al., <i>Whisker probes</i> , Ultramicroscopy 82, pp. 57-61 (2000)

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021402

EXAMINER	DATE CONSIDERED
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.	